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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10087060	02/27/2002	250		2878	

****APPLICANTS:** Saito Etsuro; Motomura Yuuichi;

****CONTINUING DATA VERIFIED:**

**** FOREIGN APPLICATIONS VERIFIED:**
JAPAN P2000-207311 07/07/2000
PCT/JP01/05921 07/06/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
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Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 21778.05600
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no	
Verified and Acknowledged Examiners's initials	

TITLE : Quantity-of-light unevenness inspection apparatus, and quantity-of-light unevenness inspection method

U.S. DEPT. OF COMM./PAT. & TM.-PTO-435L (Rev. 12-24)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
		DRAWING	
		Sheets Drwg.	Figs. Drwg.
		Print Fig.	
ISSUE FEE			
Amount Due	Date Paid		
		Application Examiner	
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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